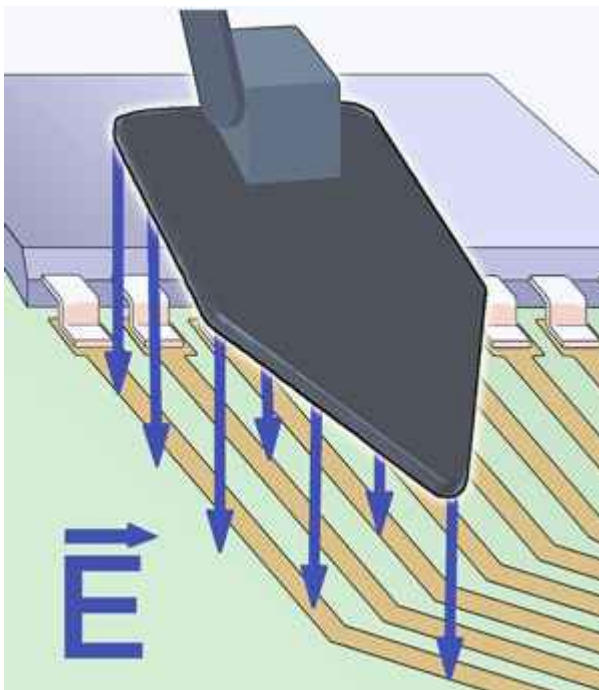


Short description

The surface of the E field source head allows the extensive coupling into housing surfaces and interior areas, connection technology and assemblies with conducting path structures and ICs (e.g. bus systems, LCD displays). Furthermore its tip can be used for the localization of small E- field sensitive weak spots (conducting paths, quartz crystal, pull-up resistance, ICs).

The resolution of ES 02 is higher than the resolution of ES 01 field source.

Measuring principles



ES 02

E-Field Source

Application ES 02

